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16-CHANNEL CONSTANT-CURRENT LED SINK DRIVERS

Check for Samples: TLC5926-Q1 TLC5927-Q1

FEATURES

- Qualified for Automotive Applications
- 16 Constant-Current Output Channels
- Output Current Adjusted By External Resistor
- Constant Output Current Range: 5 mA to 120 mA
- Constant Output Current Invariant to Load Voltage Change
- Open Load, Shorted Load, and Overtemperature Detection
- 256-Step Programmable Global Current Gain
- Excellent Output Current Accuracy:
 - Between Channels: < ±6% (Max),
 10 mA to 50 mA
 - Between ICs: < ±6% (Max), 10 mA to 50 mA

• 30-MHz Clock Frequency

- Schmitt-Trigger Input
- 3.3-V or 5-V Supply Voltage
- Thermal Shutdown for Overtemperature Protection
- ESD Performance: 2-kV HBM

APPLICATIONS

- General LED Lighting Applications
- · LED Display Systems
- LED Signage
- Automotive LED Lighting
- White Goods

DESCRIPTION/ORDERING INFORMATION

The TLC5926/TLC5927 is designed for LED displays and LED lighting applications with open-load, shorted-load, and overtemperature detection, and constant-current control. The TLC5926/TLC5927 contains a 16-bit shift register and data latches, which convert serial input data into parallel output format. At the TLC5926/TLC5927 output stage, 16 regulated-current ports provide uniform and constant current for driving LEDs within a wide range of VF (Forward Voltage) variations. Used in systems designed for LED display applications (e.g., LED panels), TLC5926/TLC5927 provides great flexibility and device performance. Users can adjust the output current from 5 mA to 120 mA through an external resistor, R_{ext}, which gives flexibility in controlling the light intensity of LEDs. TLC5926/TLC5927 is designed for up to 17 V at the output port. The high clock frequency, 30 MHz, also satisfies the system requirements of high-volume data transmission.

The TLC5926/TLC5927 provides a Special Mode in which two functions are included, Error Detection and Current Gain Control. In the TLC5926/TLC5927 there are two operation modes and three phases: Normal Mode phase, Mode Switching transition phase, and Special mode phase. The signal on the multiple-function pin $\overline{OE}(ED2)$ is monitored, and when a one-clock-wide short pulse appears on $\overline{OE}(ED2)$, TLC5926/TLC5927 enters the Mode Switching phase. At this time, the voltage level on LE(ED1) determines the next mode into which the TLC5926/TLC5927 switches.

In the Normal Mode phase, the serial data is transferred into TLC5926/TLC5927 via SDI, shifted in the shift register, and transferred out via SDO. LE(ED1) can latch the serial data in the shift register to the output latch. OE(ED2) enables the output drivers to sink current.

In the Special Mode phase, the low-voltage-level signal $\overline{\text{OE}}(\text{ED2})$ can enable output channels and detect the status of the output current, to tell if the driving current level is enough or not. The detected error status is loaded into the 16-bit shift register and shifted out via SDO, along with the CLK signal. The system controller can read the error status to determine whether or not the LEDs are properly lit. In the Special Mode phase, TLC5926/TLC5927 also allows users to adjust the output current level by setting a runtime-programmable Configuration Code. The code is sent into TLC5926/TLC5927 via SDI. The positive pulse of LE(ED1) latches the code in the shift register into a built-in 8-bit configuration latch, instead of the output latch. The code affects the voltage at R-EXT and controls the output-current regulator. The output current can be adjusted finely by a gain ranging from 1/12 to 127/128 in 256 steps. Therefore, the current skew between ICs can be compensated within less than 1%, and this feature is suitable for white balancing in LED color-display panels.



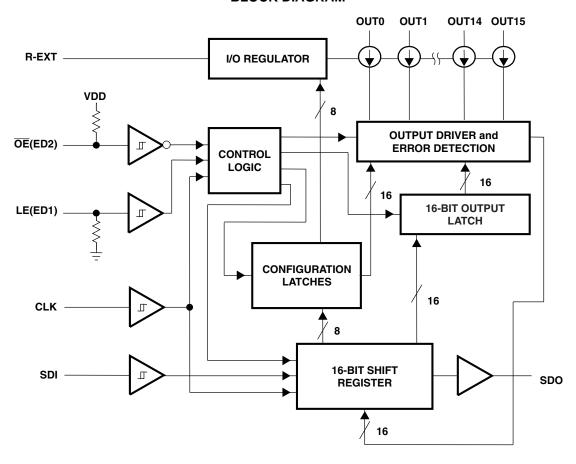
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

Table 1. ORDERING INFORMATION⁽¹⁾ (2)

T _A	PACKAGE		ORDERABLE PART NUMBER	TOP-SIDE MARKING
40°C to 405°C	PowerPAD™ – PWP	Dool of 2000	TLC5926QPWPRQ1	TLC5926Q
–40°C to 125°C	PowerPAD*** = PWP	– PWP Reel of 2000	TLC5927QPWPRQ1	TLC5927Q

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.
- (2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.

BLOCK DIAGRAM

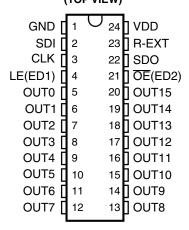


INSTRUMENTS





PWP PACKAGE (TOP VIEW)



NOTE: The exposed thermal pad should be connected to ground in all applications.

Pin Descriptions

NAME	DESCRIPTION
CLK	Clock input for data shift on rising edge
GND	Ground for control logic and current sink
LE(ED1)	Data strobe input Serial data is transferred to the respective latch when LE(ED1) is high. The data is latched when LE(ED1) goes low. Also, a control signal input for an Error Detection mode and Current Adjust mode (See Timing Diagram). LE(ED1) has an internal pulldown.
OE(ED2)	Output enable. When $\overline{\text{OE}}$ (ED2)(active) is low, the output drivers are enabled; when $\overline{\text{OE}}$ (ED2) is high, all output drivers are turned OFF (blanked). Also, a control signal input for an Error Detection mode and Current Adjust mode (See Timing Diagram). $\overline{\text{OE}}$ (ED2) has an internal pullup.
OUT0-OUT15	Constant-current output
R-EXT	Input pin used to connect an external resistor for setting up all output currents
SDI	Serial-data input to the Shift register
SDO	Serial-data output to the following SDI of next driver IC or to the microcontroller
VDD	Supply voltage
Exposed Thermal Pad	Connect to GND. The thermal pad should be soldered to ground in all applications.

Table 2. Diagnostic Features

DEVICE (1)	OPEN-LOAD DETECTION	SHORT TO GND DETECTION	SHORT TO V _{LED} DETECTION
TLC5926	x	X	
TLC5927	Х	Х	х

(1) The device has one single error register for all these conditions (one error bit per channel)

TEXAS INSTRUMENTS

Timing Diagrams

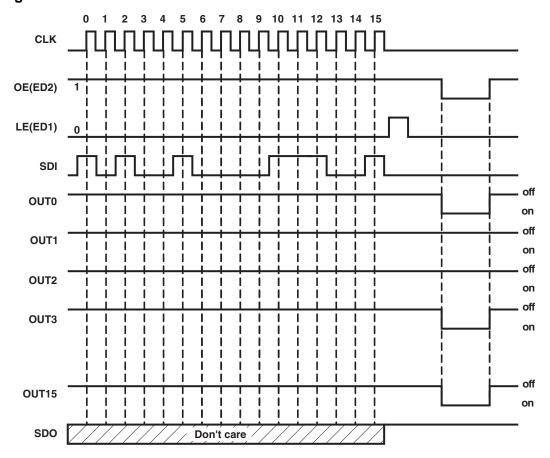


Figure 1. Normal Mode

Table 3. Truth Table in Normal Mode

CLK	LE(ED1)	OE(ED2)	SDI	OUT0OUT15	SDO
↑	Н	L	Dn	DnDn – 7Dn – 15	Dn – 15
1	L	L	Dn + 1	No change	Dn – 14
↑	Н	L	Dn + 2	Dn + 2Dn – 5Dn – 13	Dn – 13
<u> </u>	Х	L	Dn + 3	Dn + 2Dn – 5Dn – 13	Dn – 13
	Х	Н	Dn + 3	off	Dn – 13

The signal sequence shown in Figure 2 makes the TLC5926/TLC5927 enter Current Adjust and Error Detection mode.

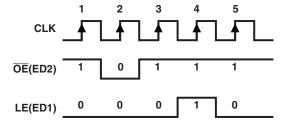


Figure 2. Switching to Special Mode



In the Current Adjust mode, sending the positive pulse of LE(ED1), the content of the shift register (a current adjust code) is written to the 16-bit configuration latch (see Figure 3).

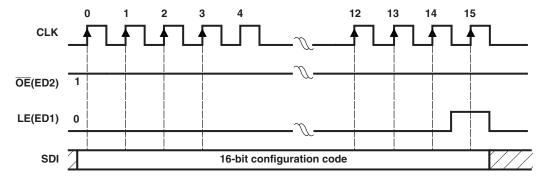


Figure 3. Writing Configuration Code

When the TLC5926/TLC5927 is in the error detection mode, the signal sequence shown in Figure 4 enables a system controller to read error status codes through SDO.

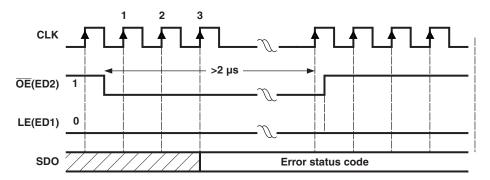


Figure 4. Reading Error Status Code

The signal sequence shown in Figure 5 makes TLC5926/TLC5927 resume the Normal mode. Switching to Normal mode resets all internal Error Status registers. \overline{OE} (ED2) always enables the output port, whether the TLC5926/TLC5927 enters current adjust mode or not.

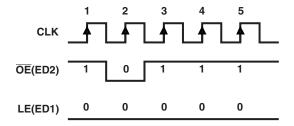


Figure 5. Switching to Normal Mode

INSTRUMENTS

TEXAS INSTRUMENTS

ABSOLUTE MAXIMUM RATINGS(1)

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V_{DD}	Supply voltage	0	7	V
V_{I}	Input voltage	-0.4	$V_{DD} + 0.4$	V
Vo	Output voltage	-0.5	20	V
I _{OUT}	Output current		120	mA
I_{GND}	GND terminal current		1920	mA
T_A	Free-air operating temperature range	-40	125	°C
T_J	Operating junction temperature range	-40	150	°C
T _{stg}	Storage temperature range	-55	150	°C
ESD	Electrostatic-discharge capability $V_{(HBMESD)}$ (100 pF, 1.5 k Ω)		2	kV

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

POWER DISSIPATION AND THERMAL IMPEDANCE

			MIN	MAX	UNIT
Ь	Power dissipation ⁽¹⁾	Mounted on JEDEC 4-layer board (JESD 51-7), No airflow, $T_A = 25$ °C, $T_J = 125$ °C		2.3	W
P_{D}	Mounted on JEDEC 4-layer board (JESD 51-5), No airflow, $I_A = 25^{\circ}$ C, $I_J = 125^{\circ}$ C			2.9	VV
		Mounted on JEDEC 1-layer board (JESD 51-3), No airflow		63.9	
θ_{JA}	Thermal impedance, junction to free air (1)	Mounted on JEDEC 4-layer board (JESD 51-7), No airflow		42.7	°C/W
	junction to not un	Mounted on JEDEC 4-layer board (JESD 51-5), No airflow		34.5	
θ_{JP}	Thermal impedance, j	unction to pad		2.0	°C/W

⁽¹⁾ The exposed thermal pad should be connected to ground in all applications.





RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		TEST C	ONDITIONS	MIN	MAX	UNIT
V_{DD}	Supply voltage			3	5.5	V
Vo	Supply voltage to the output pins	OUT0-OUT15			17	V
	Output ourrent	DC toot circuit	V _O ≥ 0.6 V	5		A
IO	Output current	ent DC test circuit	V _O ≥ 1 V		120	mA
I _{OH}	High-level output current	SDO			-1	mA
I _{OL}	Low-level output current	SDO			1	mA
V_{IH}	High-level input voltage	CLK, OE(ED2), LE(ED1)), and SDI	$0.7 \times V_{DD}$	V_{DD}	V
V_{IL}	Low-level input voltage	CLK, OE(ED2), LE(ED1)), and SDI	0	$0.3 \times V_{DD}$	V

RECOMMENDED TIMING

 $V_{DD} = 3 \text{ V to } 5.5 \text{ V (unless otherwise noted)}$

		TEST CONDITIONS	MIN MAX	UNIT
t _{w(L)}	LE(ED1) pulse duration	Normal mode	20	ns
t _{w(CLK)}	CLK pulse duration	Normal mode	20	ns
t _{w(OE)}	OE(ED2) pulse duration	Normal mode	1000	ns
t _{su(D)}	Setup time for SDI	Normal mode	7	ns
t _{h(D)}	Hold time for SDI	Normal mode	3	ns
t _{su(L)}	Setup time for LE(ED1)	Normal mode	18	ns
t _{h(L)}	Hold time for LE(ED1)	Normal mode	18	ns
t _{w(CLK)}	CLK pulse duration	Error Detection mode	20	ns
t _{w(ED2)}	OE(ED2) pulse duration	Error Detection mode	2000	ns
t _{su(ED1)}	Setup time for LE(ED1)	Error Detection mode	7	ns
t _{h(ED1)}	Hold time for LE(ED1)	Error Detection mode	10	ns
t _{su(ED2)}	Setup time for OE(ED2)	Error Detection mode	7	ns
t _{h(ED2)}	Hold time for OE(ED2)	Error Detection mode	10	ns
f _{CLK}	Clock frequency	Cascade operation, V _{DD} = 3 V to 5.5 V	30	MHz



ELECTRICAL CHARACTERISTICS

 $V_{DD} = 3 \text{ V}, T_{J} = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C} \text{ (unless otherwise noted)}$

I	PARAMETER	TEST CONI	DITIONS	MIN	TYP	MAX	UNIT
Vo	Supply voltage to the output pins					17	V
	Output ourront	V _O ≥ 0.6 V		5			mΛ
l _o	Output current	V _O ≥ 1 V				120	mA
V _{IH}	High-level input voltage			0.7 × V _{DD}		V_{DD}	V
V _{IL}	Low-level input voltage			GND		$0.3 \times V_{DD}$	V
		TLC5926, V _{OH} = 17 V	$T_J = 25^{\circ}C$			0.5	
l	Output leakage current	TLC3920, V _{OH} = 17 V	$T_J = 125$ °C			1	μA
I _{leak}	Output leakage current	TLC5927, V _{OH} = 17 V	$T_J = 25^{\circ}C$			0.5	μΛ
		1203327, VOH = 17 V	$T_J = 125$ °C			5	
V _{OH}	High-level output voltage	SDO, $I_{OL} = -1 \text{ mA}$		$V_{DD} - 0.4$			V
V _{OL}	Low-level output voltage	SDO, I _{OH} = 1 mA				0.4	V
	Output current 1	$V_{OUT} = 0.6 \text{ V}, R_{ext} = 720 \Omega,$	CG = 0.992		26		mA
I _{O(1)}	Output current error, die-to-die	$I_{OL} = 26 \text{ mA}, V_{O} = 0.6 \text{ V}, R_{e}$	$_{xt} = 720 \ \Omega, \ T_{J} = 25^{\circ}C$			±6	%
	Output current error, channel-to-channel	$I_{OL} = 26 \text{ mA}, V_{O} = 0.6 \text{ V}, R_{e}$	$x_{xt} = 720 \ \Omega, \ T_{J} = 25^{\circ}C$			±6	%
	Output current 2	$V_{O} = 0.8 \text{ V}, R_{ext} = 360 \Omega, C_{O}$	G = 0.992		52		mA
I _{O(2)}	Output current error, die-to-die	$I_{OL} = 52 \text{ mA}, V_O = 0.8 \text{ V}, R_{ext} = 360 \Omega, T_J = 25^{\circ}\text{C}$				±6	%
	Output current error, channel-to-channel	I_{OL} = 52 mA, V_{O} = 0.8 V, R_{ext} = 360 Ω,T_{J} = 25°C				±6	%
I _{OUT} vs V _{OUT}	Output current vs output voltage regulation	V _O = 1 V to 3 V, I _O = 26 mA			±0.1		0/ //
I _{OUT} vs V _{DD}	Output current vs supply voltage	$V_{DD} = 3 \text{ V to } 5.5 \text{ V}, I_{O} = 26 \text{ I}$	mA/120 mA		±1		%/V
	Pullup resistance	OE(ED2)		250	500	800	kΩ
	Pulldown resistance	LE(ED1)		250	500	800	kΩ
T _{sd}	Overtemperature shutdown (1)			150	175	200	°C
T _{hys}	Restart temperature hysteresis				15		°C
I _{OUT,Th}	Threshold current for open error detection	I _{OUT,target} = 5 mA to 120 mA			0.5 × I _{target}		%
$V_{OUT,TTh}$	Trigger threshold voltage for short-error detection (TLC5927 only)	I _{OUT,target} = 5 mA to 120 mA		2.3	2.6	3.2	V
V _{OUT, RTh}	Return threshold voltage for short-error detection (TLC5927 only)	I _{OUT,target} = 5 mA to 120 mA		1.9			V
		OUT0-OUT15 = off, R _{ext} = 0	Open, OE = V _{IH}			10	
		OUT0-OUT15 = off, $R_{ext} = 7$	$720 \overline{\Omega, \overline{OE}} = V_{IH}$			14	
		OUT0-OUT15 = off, $R_{ext} = 3$	$\overline{\Omega}, \overline{OE} = V_{IH}$			18	
I _{DD}	Supply current	OUT0-OUT15 = off, $R_{ext} = 1$	180 Ω, OE = V _{IH}			20	mA
		OUT0-OUT15 = on, R_{ext} = 720 Ω , \overline{OE} = V_{IL}				14	
		OUT0-OUT15 = on, $R_{ext} = 3$	$\overline{\Omega}, \overline{OE} = V_{IL}$			18	
		OUT0-OUT15 = on, R _{ext} = 1	180 Ω, OE = V _{IL}			20	

⁽¹⁾ Specified by design



ELECTRICAL CHARACTERISTICS

F	PARAMETER	TEST CONI	DITIONS	MIN	TYP	MAX	UNIT
V _O	Supply voltage to the output pins	W. 22V				17	V
I_	Output current	V _O ≥ 0.6 V		5			mA
l _o	Output current	V _O ≥ 1 V				120	mA
V _{IH}	High-level input voltage			$0.7 \times V_{DD}$		V_{DD}	V
V_{IL}	Low-level input voltage			GND		$0.3 \times V_{DD}$	V
		TLC5926, V _{OH} = 17 V	$T_J = 25^{\circ}C$			0.5	
l	Output leakage current	1203920, VOH = 17 V	$T_J = 125$ °C			1	μA
l _{leak}	Output leakage current	TLC5927, V _{OH} = 17 V	$T_J = 25^{\circ}C$			0.5	μΛ
		1203927, V _{OH} = 17 V	$T_J = 125$ °C			5	
√ _{OH}	High-level output voltage	SDO, $I_{OL} = -1 \text{ mA}$		$V_{DD} - 0.4$			V
V _{OL}	Low-level output voltage	SDO, I _{OH} = 1 mA				0.4	V
	Output current 1	$V_{OUT} = 0.6 \text{ V}, R_{ext} = 720 \Omega,$	CG = 0.992		26		mA
O(1)	Output current error, die-to-die	$I_{OL} = 26 \text{ mA}, V_{O} = 0.6 \text{ V}, R_{e}$	_{xt} = 720 Ω, T _J = 25°C			±6	%
	Output current error, channel-to-channel	$I_{OL} = 26 \text{ mA}, V_{O} = 0.6 \text{ V}, R_{e}$	_{xt} = 720 Ω, T _J = 25°C			±6	%
	Output current 2	$V_{\rm O} = 0.8 \text{ V}, R_{\rm ext} = 360 \Omega, {\rm CG} = 0.992$ 52			mA		
O(2)	Output current error, die-to-die		$I_{OL} = 52 \text{ mA}, V_O = 0.8 \text{ V}, R_{ext} = 360 \Omega, T_J = 25^{\circ}\text{C}$			±6	%
	Output current error, channel-to-channel	$I_{OL} = 52 \text{ mA}, V_O = 0.8 \text{ V}, R_{ext} = 360 \Omega, T_J = 25^{\circ}\text{C}$				±6	%
I _{OUT} vs V _{OUT}	Output current vs output voltage regulation	V _O = 1 V to 3 V, I _O = 26 mA			±0.1		0/ /\
I _{OUT} vs V _{DD}	Output current vs supply voltage	$V_{DD} = 3 \text{ V to } 5.5 \text{ V, } I_{O} = 26 \text{ I}$	V _{DD} = 3 V to 5.5 V, I _O = 26 mA/120 mA		±1		%/\/
	Pullup resistance	OE(ED2)		250	500	800	kΩ
	Pulldown resistance	LE(ED1)		250	500	800	kΩ
Γ _{sd}	Overtemperature shutdown ⁽¹⁾			150	175	200	°C
T _{hys}	Restart temperature hysteresis				15		°C
OUT,Th	Threshold current for open error detection	I _{OUT,target} = 5 mA to 120 mA			0.5 x I _{target}		%
$V_{OUT,TTh}$	Trigger threshold voltage for short-error detection (TLC5927 only)	I _{OUT,target} = 5 mA to 120 mA		2.3	2.6	3.2	V
V _{OUT, RTh}	Return threshold voltage for short-error detection (TLC5927 only)	I _{OUT,target} = 5 mA to 120 mA		1.9			V
		OUT0-OUT15 = off, $R_{ext} = 0$	Open, OE = V _{IH}			11	
		OUT0-OUT15 = off, $R_{ext} = 7$	$ \overline{\Omega}, \overline{OE} = V_{IH} $			17	
		OUT0-OUT15 = off, R_{ext} = 360 Ω , \overline{OE} = V_{IH}				18	
DD	Supply current	OUT0-OUT15 = off, R_{ext} = 180 Ω , $\overline{\text{OE}}$ = V_{IH}				25	mΑ
		OUT0-OUT15 = on, $R_{ext} = 7$				17	
		OUT0-OUT15 = on, R _{ext} = 3				18	
		OUT0-OUT15 = on, R _{ext} = 1		1		25	

⁽¹⁾ Specified by design



TEXAS INSTRUMENTS

SWITCHING CHARACTERISTICS

 V_{DD} = 3 V, T_J = -40°C to 125°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH1}	Low-to-high propagation delay time, CLK to OUTn		35	65	105	ns
t _{PLH2}	Low-to-high propagation delay time, LE(ED1) to OUTn		35	65	105	ns
t _{PLH3}	Low-to-high propagation delay time, $\overline{\text{OE}}(\text{ED2})$ to OUTn		35	65	105	ns
t _{PLH4}	Low-to-high propagation delay time, CLK to SDO			20	45	ns
t _{PHL1}	High-to-low propagation delay time, CLK to OUTn		200	300	470	ns
t _{PHL2}	High-to-low propagation delay time, LE(ED1) to OUTn		200	300	470	ns
t _{PHL3}	High-to-low propagation delay time, $\overline{\sf OE}({\sf ED2})$ to OUTn		200	300	470	ns
t _{PHL4}	High-to-low propagation delay time, CLK to SDO			20	40	ns
t _{w(CLK)}	Pulse duration, CLK		20			ns
t _{w(L)}	Pulse duration LE(ED1)	$V_{IH} = V_{DD}, V_{IL} = GND,$	20			ns
t _{w(OE)}	Pulse duration, OE(ED2)	$R_{\text{ext}} = 360 \ \Omega, \ V_{\text{L}} = 4 \ \text{V},$ $R_{\text{L}} = 44 \ \Omega, \ C_{\text{L}} = 70 \ \text{pF},$	1000			ns
t _{w(ED2)}	Pulse duration, OE(ED2) in Error Detection mode	CG = 0.992	2			μs
t _{h(ED1,ED2)}	Hold time, LE(ED1), and $\overline{\text{OE}}(\text{ED2})$		10			ns
t _{h(D)}	Hold time, SDI		5			ns
t _{su(D,ED1,ED2)}	Setup time, SDI, LE(ED1), and OE(ED2)		7			ns
t _{h(L)}	Hold time, LE(ED1), Normal mode		18			ns
t _{su(L)}	Setup time, LE(ED1), Normal mode		18			ns
t _r	Rise time, CLK ⁽¹⁾				500	ns
t _f	Fall time, CLK ⁽¹⁾				500	ns
t _{or}	Rise time, outputs (off)				245	ns
t _{of}	Rise time, outputs (on)				600	ns
f _{CLK}	Clock frequency	Cascade operation			30	MHz

⁽¹⁾ If the devices are connected in cascade and t_r or t_f is large, it may be critical to achieve the timing required for data transfer between two cascaded devices.

Product Folder Link(s): TLC5926-Q1 TLC5927-Q1



SWITCHING CHARACTERISTICS

 $V_{DD} = 5.5 \text{ V}, T_{\perp} = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C} \text{ (unless otherwise noted)}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH1}	Low-to-high propagation delay time, CLK to OUTn		27	65	95	ns
t _{PLH2}	Low-to-high propagation delay time, LE(ED1) to OUTn	V _{IH} = V _{DD} , V _{IL} = GND, R _{ext} = $360~\Omega$, V _L = $4~V$, R _L = $44~\Omega$, C _L = $70~pF$, CG = 0.992	27	65	95	ns
t _{PLH3}	Low-to-high propagation delay time, $\overline{\text{OE}}(\text{ED2})$ to OUTn		27	65	95	ns
t _{PLH4}	Low-to-high propagation delay time, CLK to SDO			20	30	ns
t _{PHL1}	High-to-low propagation delay time, CLK to OUTn		180	300	445	ns
t _{PHL2}	High-to-low propagation delay time, LE(ED1) to OUTn		180	300	445	ns
t _{PHL3}	High-to-low propagation delay time, $\overline{\sf OE}({\sf ED2})$ to OUTn		180	300	445	ns
t _{PHL4}	High-to-low propagation delay time, CLK to SDO			20	30	ns
$t_{w(CLK)}$	Pulse duration, CLK		20			ns
t _{w(L)}	Pulse duration LE(ED1)	$V_{IH} = V_{DD}, V_{IL} = GND,$	20			ns
$t_{w(OE)}$	Pulse duration, OE(ED2)	$R_{\text{ext}} = 360 \Omega, V_{\text{L}} = 4 V,$ $R_{\text{L}} = 44 \Omega, C_{\text{L}} = 70 \text{pF}.$	1000			ns
$t_{w(ED2)}$	Pulse duration, OE(ED2) in Error Detection mode		2			μs
$t_{h(ED1,ED2)}$	Hold time, LE(ED1), and $\overline{\text{OE}}(\text{ED2})$		10			ns
$t_{h(D)}$	Hold time, SDI		3			ns
t _{su(D,ED1,ED2)}	Setup time, SDI, LE(ED1), and $\overline{\text{OE}}(\text{ED2})$		4			ns
t _{h(L)}	Hold time, LE(ED1), Normal mode		15			ns
$t_{su(L)}$	Setup time, LE(ED1), Normal mode		15			ns
t _r	Rise time, CLK ⁽¹⁾				500	ns
t _f	Fall time, CLK ⁽¹⁾				500	ns
t _{or}	Rise time, outputs (off)				245	ns
t _{of}	Rise time, outputs (on)				570	ns
f _{CLK}	Clock frequency	Cascade operation			30	MHz

⁽¹⁾ If the devices are connected in cascade and t_r or t_f is large, it may be critical to achieve the timing required for data transfer between two cascaded devices.

PARAMETER MEASUREMENT INFORMATION

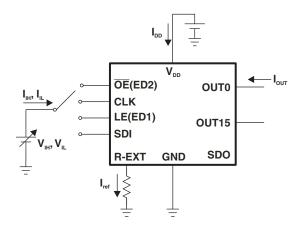


Figure 6. Test Circuit for Electrical Characteristics

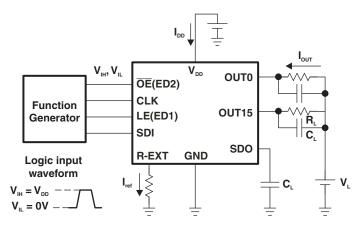


Figure 7. Test Circuit for Switching Characteristics



PARAMETER MEASUREMENT INFORMATION (continued)

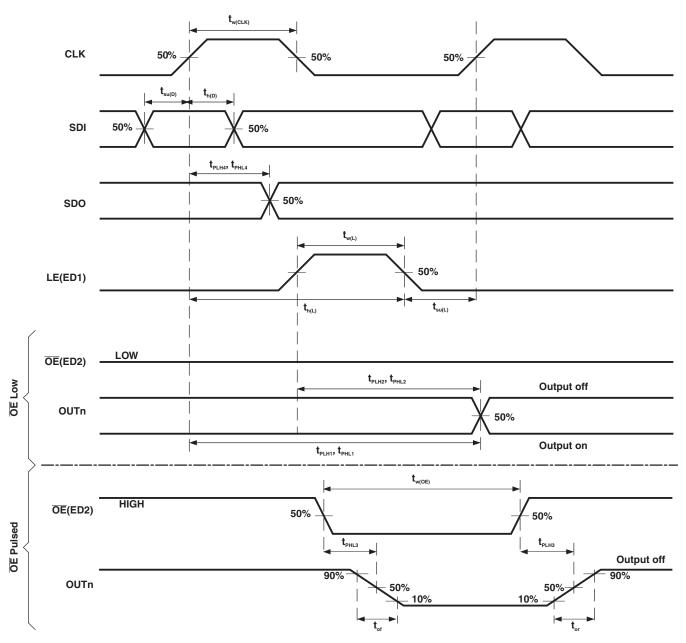


Figure 8. Normal Mode Timing Waveforms

PARAMETER MEASUREMENT INFORMATION (continued)

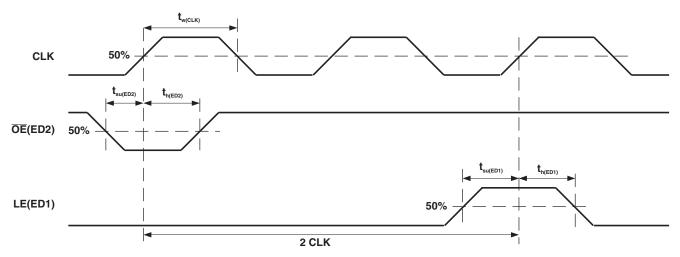


Figure 9. Switching to Special Mode Timing Waveforms

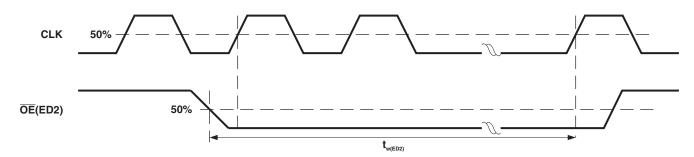


Figure 10. Reading Error Status Code Timing Waveforms

APPLICATION INFORMATION

Operating Principles

Constant Current

In LED display applications, TLC5926/TLC5927 provides nearly no current variations from channel to channel and from IC to IC. While $I_{OUT} \le 50$ mA, the maximum current skew between channels is less than $\pm 6\%$ and between ICs is less than $\pm 6\%$.

Adjusting Output Current

TLC5926/TLC5927 scales up the reference current, I_{ref} , set by the external resistor R_{ext} to sink a current, I_{out} , at each output port. Users can follow the below formulas to calculate the target output current $I_{OUT,target}$ in the saturation region:

$$V_{R-FXT} = 1.26 \text{ V} \times \text{VG}$$

 $I_{ref} = V_{R-EXT}/R_{ext}$, if another end of the external resistor R_{ext} is connected to ground.

$$I_{OUT,target} = I_{ref} \times 15 \times 3^{CM-1}$$

Where R_{ext} is the resistance of the external resistor connected to the R-EXT terminal, and $V_{\text{R-EXT}}$ is the voltage of R-EXT, which is controlled by the programmable voltage gain (VG), which is defined by the Configuration Code. The Current Multiplier (CM) determines that the ratio $I_{\text{OUT,target}}/I_{\text{ref}}$ is 15 or 5. After power on, the default value of VG is 127/128 = 0.992, and the default value of CM is 1, so that the ratio $I_{\text{OUT,target}}/I_{\text{ref}}$ = 15. Based on the default VG and CM.

$$V_{R-EXT} = 1.26 \text{ V} \times 127/128 = 1.25 \text{ V}$$

$$I_{OUT,target} = (1.25 \text{ V/R}_{ext}) \times 15$$

Therefore, the default current is approximately 52 mA at 360 Ω and 26 mA at 720 Ω . The default relationship after power on between $I_{OUT,target}$ and R_{ext} is shown in Figure 11.

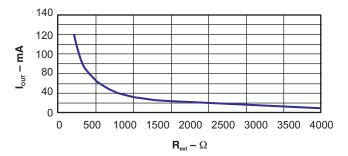


Figure 11. Default Relationship Curve Between I_{OUT,target} and R_{ext}

INSTRUMENTS

Operation Phases

Operation Mode Switching

In order to switch between its two modes, TLC5926/TLC5927 monitors the signal OE(ED2). When a one-clock-wide pulse of OE(ED2) appears, TLC5926/TLC5927 enters the two-clock-period transition phase, the Mode Switching phase. After power on, the default operation mode is the Normal Mode (see Figure 12).

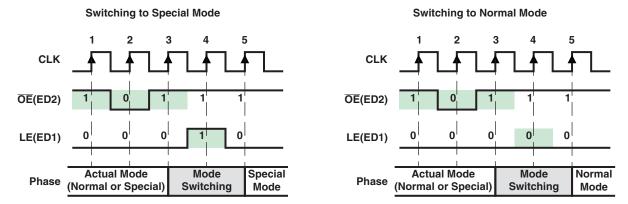


Figure 12. Mode Switching

As shown in Figure 12, once a one-clock-wide short pulse (101) of $\overline{\text{OE}}(\text{ED2})$ appears, TLC5926/TLC5927 enters the Mode Switching phase. At the fourth rising edge of CLK, if LE(ED1) is sampled as voltage high, TLC5926/TLC5927 switches to Special mode; otherwise, it switches to Normal mode. The signal LE(ED1) between the third and the fifth rising edges of CLK cannot latch any data. Its level is used only to determine into which mode to switch. However, the short pulse of $\overline{\text{OE}}(\text{ED2})$ can still enable the output ports. During mode switching, the serial data can still be transferred through SDI and shifted out from SDO.

NOTES:

- 1. The signal sequence for the mode switching may be used frequently to ensure that the TLC5926/TLC5927 is in the proper mode.
- 2. The 1 and 0 on the LE(ED1) signal are sampled at the rising edge of CLK. The X means its level does not affect the result of mode switching mechanism.
- 3. After power on, the default operation mode is Normal mode.

Normal Mode Phase

Serial data is transferred into TLC5926/TLC5927 via SDI, shifted in the Shift Register, and output via SDO. LE(ED1) can latch the serial data in the Shift Register to the Output Latch. OE(ED2) enables the output drivers to sink current. These functions differ only as described in Operation Mode Switching, in which case, a short pulse triggers TLC5926/TLC5927 to switch the operation mode. However, as long as LE(ED1) is high in the Mode Switching phase, TLC5926/TLC5927 remains in the Normal mode, as if no mode switching occurred.

Special Mode Phase

In the Special mode, as long as $\overline{\text{OE}}(\text{ED2})$ is not low, the serial data is shifted to the Shift Register via SDI and shifted out via SDO, as in the Normal mode. However, there are two differences between the Special Mode and the Normal Mode, as shown in the following sections.



Reading Error Status Code in Special Mode

INSTRUMENTS

When $\overline{\text{OE}}(\text{ED2})$ is pulled low while in Special mode, error detection and load error status codes are loaded into the Shift Register, in addition to enabling output ports to sink current. Figure 13 shows the timing sequence for error detection. The 0 and 1 signal levels are sampled at the rising edge of each CLK. At least three zeros must be sampled at the voltage low signal $\overline{\text{OE}}(\text{ED2})$. Immediately after the second 0 is sampled, the data input source of the Shift Register changes to the 16-bit parallel Error Status Code register, instead of from the serial data on SDI. Normally, the error status codes are generated at least 2 μ s after the falling edge of $\overline{\text{OE}}(\text{ED2})$. The occurrence of the third or later 0 saves the detected error status codes into the Shift Register. Therefore, when $\overline{\text{OE}}(\text{ED2})$ is low, the serial data cannot be shifted into TLC5926/TLC5927 via SDI. When $\overline{\text{OE}}(\text{ED2})$ is pulled high, the data input source of the Shift Register is changed back to SDI. At the same time, the output ports are disabled and the error detection is completed. Then, the error status codes saved in the Shift Register can be shifted out via SDO bit-by-bit along with CLK, as well as the new serial data can be shifted into TLC5926/TLC5927 via SDI.

While in Special mode, the TLC5926/TLC5927 cannot simultaneously transfer serial data and detect LED load error status.

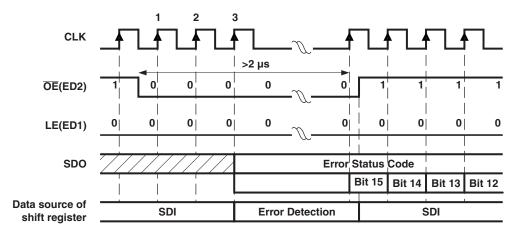


Figure 13. Reading Error Status Code

Writing Configuration Code in Special Mode

When in Special mode, the active high signal LE(ED1) latches the serial data in the Shift Register to the Configuration Latch, instead of the Output Latch. The latched serial data is used as the Configuration Code.

The code is stored until power off or the Configuration Latch is rewritten. As shown in Figure 14, the timing for writing the Configuration Code is the same as the timing in the Normal Mode to latching output channel data. Both the Configuration Code and Error Status Code are transferred in the common 16-bit Shift Register. Users must pay attention to the sequence of error detection and current adjustment to avoid the Configuration Code being overwritten by Error Status Code.

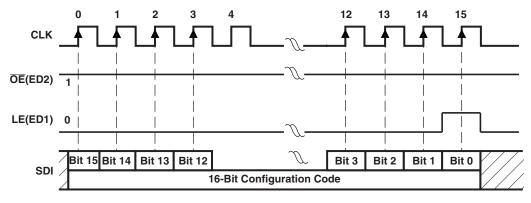


Figure 14. Writing Configuration Code

TEXAS INSTRUMENTS

Open-Circuit Detection Principle

The LED Open-Circuit Detection compares the effective current level I_{OUT} with the open load detection threshold current $I_{OUT,Th}$. If I_{OUT} is below the $I_{OUT,Th}$ threshold, the TLC5926/TLC5927 detects an open-load condition. This error status can be read as an error status code in the Special mode. For open-circuit error detection, a channel must be on.

Table 4. Open-Circuit Detection

STATE OF OUTPUT PORT	CONDITION OF OUTPUT CURRENT	ERROR STATUS CODE	MEANING
Off	I _{OUT} = 0 mA	0	Detection not possible
0	I _{OUT} < I _{OUT,Th} ⁽¹⁾	0	Open circuit
On	I _{OUT} ≥ I _{OUT,Th} ⁽¹⁾	1	Normal

⁽¹⁾ $I_{OUT,Th} = 0.5 \times I_{OUT,target}$ (typical)

Short-Circuit Detection Principle (TLC5927 Only)

The LED short-circuit detection compares the effective voltage level V_{OUT} with the shorted-load detection threshold voltages $V_{OUT,TTh}$ and $V_{OUT,RTh}$. If V_{OUT} is above the $V_{OUT,TTh}$ threshold, the TLC5927 detects a shorted-load condition. If the V_{OUT} is below $V_{OUT,RTh}$ threshold, no error is detected and the error bit is reset. This error status can be read as an error status code in the Special mode. For short-circuit error detection, a channel must be on.

Table 5. Short-Circuit Detection

STATE OF OUTPUT PORT	CONDITION OF OUTPUT VOLTAGE	ERROR STATUS CODE	MEANING	
Off	I _{OUT} = 0 mA	0	Detection not possible	
0.5	$V_{OUT} \ge V_{OUT,TTh}$	0	Short circuit	
On	V _{OUT} < V _{OUT,RTh}	1	Normal	

Overtemperature Detection and Shutdown

The TLC5926/TLC5927 is equipped with a global overtemperature sensor and 16 individual, channel-specific overtemperature sensors.

- When the global sensor reaches the trip temperature, all output channels are shutdown, and the error status is stored in the internal Error Status register of every channel. After shutdown, the channels automatically restart after cooling down, if the control signal (output latch) remains on. The stored error status is not reset after cooling down and can be read out as the error status code in the Special mode.
- When one of the channel-specific sensors reaches trip temperature, only the affected output channel is shut down, and the error status is stored only in the internal Error Status register of the affected channel. After shutdown, the channel automatically restarts after cooling down, if the control signal (output latch) remains on. The stored error status is not reset after cooling down and can be read out as error status code in the Special mode.

For channel-specific overtemperature error detection, a channel must be on.

The error status code is reset when the TLC5926/TLC5927 returns to Normal mode.



Table 6. Overtemperature D	etection ⁽¹⁾
----------------------------	-------------------------

STATE OF OUTPUT PORT	CONDITION	ERROR STATUS CODE	MEANING	
Off	I _{OUT} = 0 mA	0		
On	T _j < T _{j,trip} global	1	Normal	
On → all channels Off	T _j > T _{j,trip} global	All error status bits = 0	Global overtemperature	
On	$T_j < T_{j,trip}$ channel n	1	Normal	
$On \rightarrow Off$	$T_j > T_{j,trip}$ channel n	Channel n error status bit = 0	Channel n overtemperature	

⁽¹⁾ The global shutdown threshold temperature is approximately 170°C.

16-Bit Configuration Code and Current Gain

Bit definition of the Configuration Code in the Configuration Latch is shown in Table 7.

Table 7. Bit Definition of 8-Bit Configuration Code

	Bit 0	Bit 1	Bit 2	Bit 3	Bit 4	Bit 5	Bit 6	Bit 7	Bit 8–15
Meaning	CM	HC	CC0	CC1	CC2	CC3	CC4	CC5	Don't care
Default	1	1	1	1	1	1	1	1	Х

Bit 7 is first sent into TLC5926/TLC5927 via SDI. Bits 1 to 7 {HC, CC[0:5]} determine the voltage gain (VG) that affects the voltage at R-EXT and indirectly affects the reference current, I_{ref}, flowing through the external resistor at R-EXT. Bit 0 is the Current Multiplier (CM) that determines the ratio I_{OUT,target}/I_{ref}. Each combination of VG and CM gives a specific Current Gain (CG).

• VG: the relationship between {HC,CC[0:5]} and the voltage gain is calculated as:

$$VG = (1 + HC) \times (1 + D/64) / 4$$

$$D = CC0 \times 2^5 + CC1 \times 2^4 + CC2 \times 2^3 + CC3 \times 2^2 + CC4 \times 2^1 + CC5 \times 2^0$$

Where HC is 1 or 0, and D is the binary value of CC[0:5]. So, the VG could be regarded as a floating-point number with 1-bit exponent HC and 6-bit mantissa CC[0:5]. {HC,CC[0:5]} divides the programmable voltage gain VG into 128 steps and two sub-bands:

Low voltage sub-band (HC = 0): VG = 1/4 ~ 127/256, linearly divided into 64 steps

High voltage sub-band (HC = 1): VG = 1/2 ~ 127/128, linearly divided into 64 steps

CM: In addition to determining the ratio I_{OUT,target}/I_{ref}, CM limits the output current range.

High Current Multiplier (CM = 1): $I_{OUT,target}/I_{ref}$ = 15, suitable for output current range I_{OUT} = 10 mA to 120 mA. Low Current Multiplier (CM = 0): $I_{OUT,target}/I_{ref}$ = 5, suitable for output current range I_{OUT} = 5 mA to 40 mA

· CG: The total Current Gain is defined as the following.

$$V_{R-FXT} = 1.26 \text{ V} \times \text{VG}$$

 $I_{ref} = V_{R-EXT}/R_{ext}$, if the external resistor, R_{ext} , is connected to ground.

$$I_{OUT,target} = I_{ref} \times 15 \times 3^{CM-1} = 1.26 \text{ V/R}_{ext} \times \text{VG} \times 15 \times 3^{CM-1} = (1.26 \text{ V/R}_{ext} \times 15) \times \text{CG}$$

 $CG = VG \times 3^{CM-1}$

Therefore, CG = (1/12) to (127/128) divided into 256 steps.

Examples

• Configuration Code {CM, HC, CC[0:5]} = {1,1,111111}

$$VG = 127/128 = 0.992$$
 and $CG = VG \times 3^0 = VG = 0.992$

Configuration Code = {1,1,000000}

$$VG = (1 + 1) \times (1 + 0/64)/4 = 1/2 = 0.5$$
, and $CG = 0.5$

• Configuration Code = {0,0,000000}

$$VG = (1 + 0) \times (1 + 0/64)/4 = 1/4$$
, and $CG = (1/4) \times 3^{-1} = 1/12$

After power on, the default value of the Configuration Code $\{CM, HC, CC[0:5]\}$ is $\{1,1,111111\}$. Therefore, VG = CG = 0.992. The relationship between the Configuration Code and the Current Gain is shown in Figure 15.

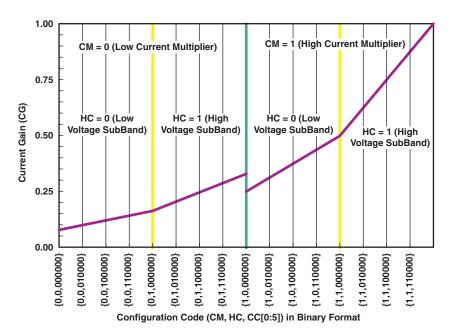


Figure 15. Current Gain vs Configuration Code



PACKAGE OPTION ADDENDUM



11-Apr-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	U	Pins	U	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
	(1)		Drawing		Qty	(2)		(3)		(4)	
TLC5926QPWPRQ1	ACTIVE	HTSSOP	PWP	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	TLC5926Q	Samples
TLC5927QPWPRQ1	ACTIVE	HTSSOP	PWP	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	TLC5927Q	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

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OTHER QUALIFIED VERSIONS OF TLC5926-Q1, TLC5927-Q1:



PACKAGE OPTION ADDENDUM

11-Apr-2013

• Catalog: TLC5926, TLC5927

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NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLC5927QPWPRQ1	HTSSOP	PWP	24	2000	330.0	16.4	6.95	8.3	1.6	8.0	16.0	Q1

www.ti.com 8-Apr-2013



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
TLC5927QPWPRQ1	HTSSOP	PWP	24	2000	367.0	367.0	38.0	

PWP (R-PDSO-G24)

PowerPAD™ PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- This drawing is subject to change without notice.
- Body dimensions do not include mold flash or protrusions. Mold flash and protrusion shall not exceed 0.15 per side.
- This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com http://www.ti.com.

 E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- E. Falls within JEDEC MO-153

PowerPAD is a trademark of Texas Instruments.



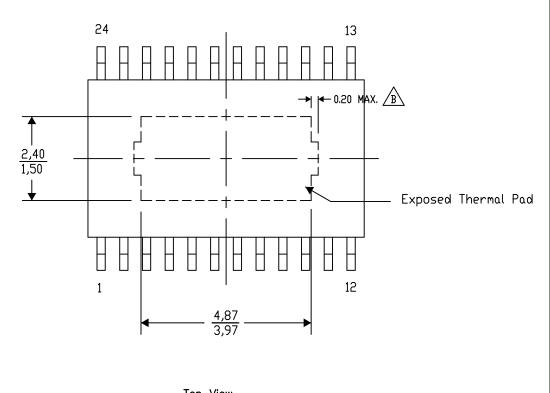
PWP (R-PDSO-G24) PowerPAD™ SMALL PLASTIC OUTLINE

THERMAL INFORMATION

This PowerPAD[™] package incorporates an exposed thermal pad that is designed to be attached to a printed circuit board (PCB). The thermal pad must be soldered directly to the PCB. After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For additional information on the PowerPAD package and how to take advantage of its heat dissipating abilities, refer to Technical Brief, PowerPAD Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 and Application Brief, PowerPAD Made Easy, Texas Instruments Literature No. SLMA004. Both documents are available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Top View

Exposed Thermal Pad Dimensions

4206332-29/AD 01/13

NOTE: A. All linear dimensions are in millimeters

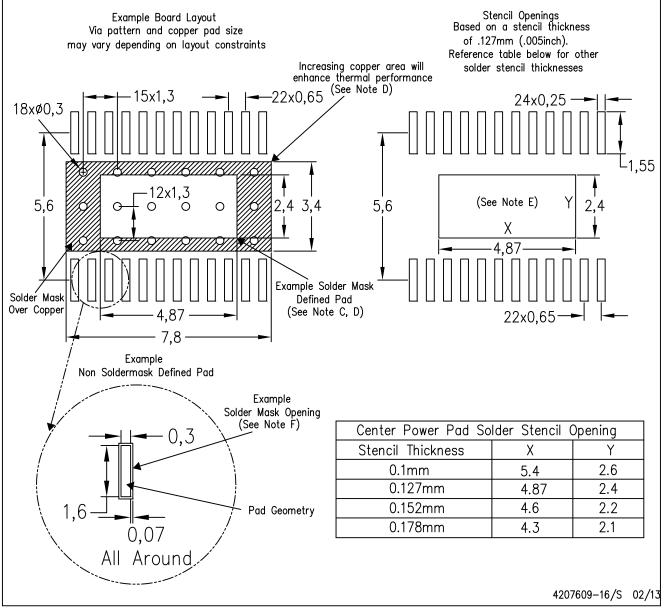
/B\ Exposed tie strap features may not be present.

PowerPAD is a trademark of Texas Instruments



PWP (R-PDSO-G24)

PowerPAD™ PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002, SLMA004, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC—7525 for other stencil recommendations.
- F. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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